







Surface Texture and Contour Integrated Measuring Instrument

SURFCOM IN 13/7

Linear Technology

Integrated measuring instrument with the highest accuracy in its class

Newly developed dual sensor technology enables roughness and contour measurements at a time

Retrofit increases the value of an existing machine (Linear series)

${f 01}$ Newly Developed Dual Sensor Technology





Single hybrid detector makes surface texture and contour measurements possible at a time!

This saves operator's time to exchange detectors and greatly improves work efficiency.

High resolution
Differential inductance

Resolution/measuring range
1.0 nm/0.05 mm to 100 nm/5 mm

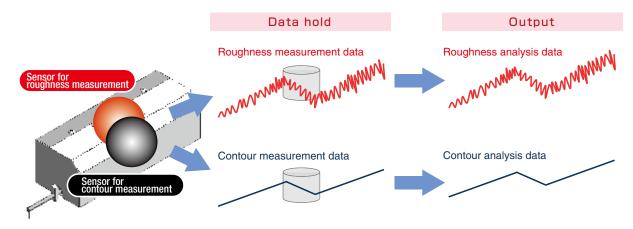


(High-accuracy scale)

Z-axis indication accuracy $\pm (1.0+ \mid 2H \mid /100) \mu m$

■ Principle of SURCOM NEX 100 Dual Sensor Technology

New hybrid detector mounts two sensors and acquires each roughness and contour signals at the same time.





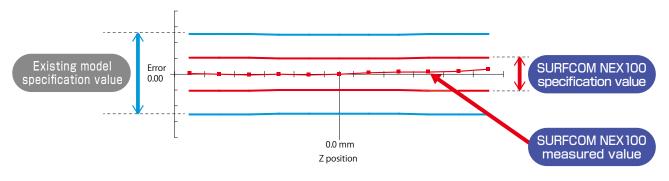
02 Highest Accuracy in its Class



Z-axis indication accuracy has been improved to $\pm (1.0+|2H|/100) \, \mu m^{^{^{1}}}$ from $\pm (2.5+|2H|/100) \, \mu m^{^{^{2}}}$

Accuracy improved from 2.55 μm to 1.05 μm at 2.5 mm of full stroke. *1 SURFCOM

*1 SURFCOM NEX 100
*2 Existing model



03 Larger Standard Granite Table

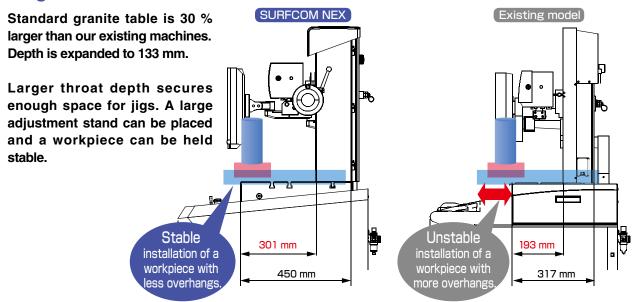
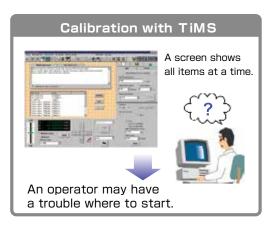


Image of the use of Y-axis CNC table (200 mm)

04 Calibration Wizard Function (Standard)

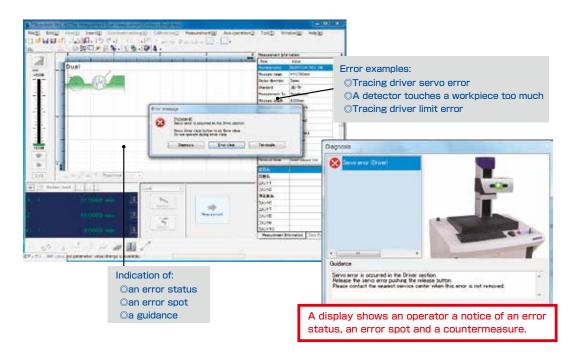
Wizard function enables even a beginner to conduct a calibration.

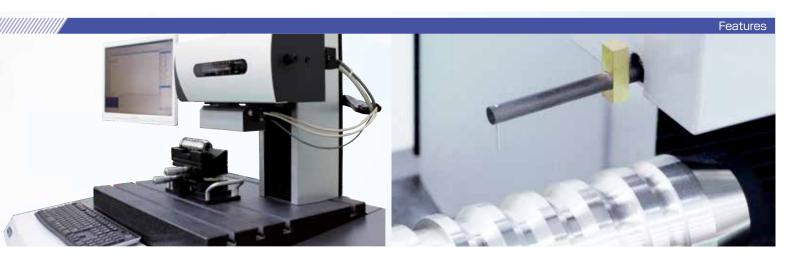




05 Self-Diagnosis Function (Standard)

In preparation for an emergency, the self-diagnosis function is always in operation. Whenever there is a problem, a message indicating the location and nature of the problem such as a failure or error with the measurement instrument screen is displayed, enabling the operator to take appropriate action in to resolve the problem as soon as possible.

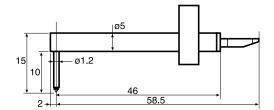




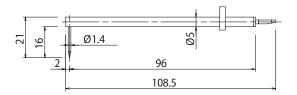
06 Styli for SURFCOM NEX 100

Two replaceable styli are standard accessories.

Stylus for roughness and contour DM48507: 2 µmR, LH=50, LV=-15.5, 0.75 mN



 Stylus for roughness and contour DM48775: 25μmR, LH=100, LV=-21.5, 4mN



Note: Styli for S2000 can not be used to SURFCOM NEX 100.

07 Retrofit Increases the Value of an Existing Machine

Linear series machines can be retrofit by SURFCOM NEX. Expanded functionality enhances the operational efficiency.



Specialized machine for roughness measurement



Contour measurement also available

Upgrade to integrated machine for roughness and contour measurement



Specialized machine for contour measurement



Roughness measurement also available

Upgrade to integrated machine for roughness and contour measurement



Combined machine for roughness and contour measurement



Roughness and contour measurement available without detector exchange

Upgrade to integrated machine

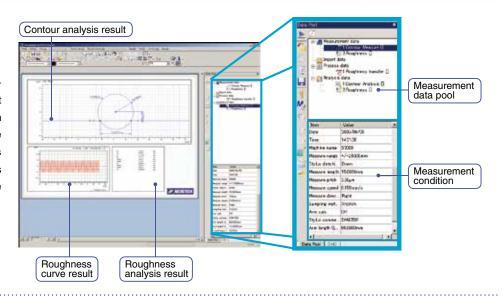
Dual sensor technology upgrades an existing machine as a high accuracy integrated machine for roughness and contour measurement without exchanging detectors.

*Note: Applicable software is only ACCTee after retrofit.



Leading-edge **Operability**

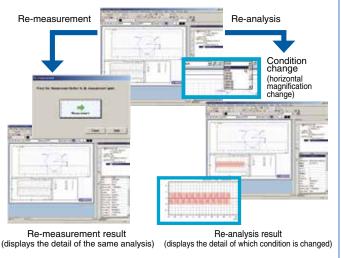
ACCTee is equipped with a Windows style user interface that anyone can easily access. High operability is achieved with the user-friendly and intuitive icons that assist a series of operations from the measurement to the printing of analysis results.



Efficiency Improvement of Re-analysis and Re-measurement with Easy Operation

ACCTee contains all the information including the layout, measurement condition, analysis condition, measurement data, and part program in the document, so that the data edit, addition, reanalysis, and re-measurement of the analysis details can be executed freely. Since the switchover between windows is not necessary, it improves the operational efficiency by 40% or more compared with the conventional software. Besides executing re-analysis, when executing the same measurement and analysis of the previous times, the measurement result similar to the previous time can be acquired by selecting the measurement data of the data pool and clicking the remeasurement data.

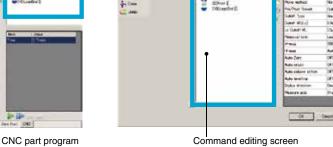




CNC Function

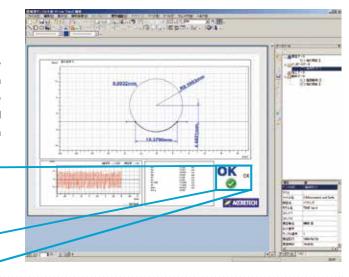
This provides a highly efficient measurement work environment. as the series of tasks, from the measurement to the output of the test result, can be executed automatically. For the case and calculation error in the measurement result, such operations as "Jump", "Pause", "Stop" and "Continue" can be chosen. Because of the system call command, you can display any type of image files during CNC operation, and can check the part setup and stylus configuration with photos so that you can avoid accidental errors in advance.





Document Comprehensive Judgment Display

ACCTee can provide judgment concerning the 16% rule and the design value for individual parameters. It can also display OK/NG in the graphic image for comprehensive judgment relating to the whole document. As a preset master page is registered, your logo and desired background will appear on all pages of the final inspection sheet output.



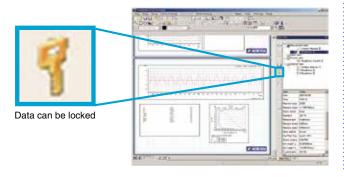






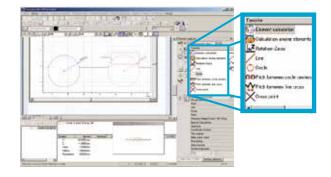
Software Data Protection

The data measured by ACCTee can be protected by locking the data, eliminating the unintended data clear or data exchange, so that accidental data loss can be prevented.



Favorite

Frequently used commands can be stored in "Favorite" and reorganized for easy use.



Multi Languages Support

ACCTee can be used overseas and supports several languages including Japanese, Chinese, Korean, English, German, French, Italian, Spanish, Czech and Polish.



Language select screen

Help System

Help is always available whenever ACCTee is on. ACCTee features an on-line manual system so that an appropriate help message can be displayed by clicking the soft help key.

Help can also be obtained by browsing the index or searching with keywords.



Measuring Unit

Model							SURFC	OM NEX				
Model				12	13	14	15	22	23	24	25	
Measuring	Z-axis (E	Detector: verti	cal direction)		•	5 mm /	Standard a	m, 10 mm /	2x arm			
range	<u> </u>	racing driver: horiz				mm				mm		
Max. meas	uring heig	ht (Column up		250 mm	250 mm 450 mm 650 mm 250 mm 450 mm 650 mr							
		Sensing met	thod				Differential	inductance			··•	
	Roughness	Measuring r	ange		•		•	to 5.0 mm		***************************************		
		Resolution					1.0 nm to	o 100 nm				
		Sensing met	Sensing method			_	High-accu	iracy scale		_		
	Contour	Measuring r	Measuring range			_	5.0	mm			_	
		Indication acc	curacy (vertical)	± (1.	0+ 2H /100)) μm (H:	Measuring h	neight) (Whe	en LH=50 m	nm stylus is	used)	
Hybrid		For	Model			(L	DM4 H=50 mm, S	8507 Standard arr	n)			
detector		Roughness	Measuring force				0.75 ı	•		•		
with dual sensor		and Contour	Material		Diamond							
technology			Tip shape		2 μmR/60° cone							
5,	Stylus		Model	DM48775 (LH=100 mm, 2x arm)								
		For Contour	Measuring force	4.0 mN								
			Material	4.0 min								
			Tip shape	•	25 µmR/24° cone							
		Replacement method		Replaceable								
	Commo	n Function	itilietiloa	Upper limit detection safety mechanism / retract function								
	Commo	Sensing me	ethod		Орре	i iiiiiii detec		r scale	/ Tetract rui	iction		
		Straightnes		(0.05+1.0 L/1000) μm								
		V avis indication	accuracy (horizontal)	⊥ / 1	0 1 01 /10	0)μm (L:	0.15 μm		on I U_E0m	on stulus is		
Tracing driver	X-axis	Resolution	accuracy (HOHZOHIAI)		.0+1.0L/10	υ) μπ (L:	•	ength) (wh μ m	en Ln=3011	iiii stylus is	usea)	
unver		Resolution	Moving speed	•	•		•	to 60 mm/s	•	•		
		Speed	Measuring speed	•	•		•	•		•	··•	
		Tilt angle	ivieasuring speeu		0.03 mm/s to 20 mm/s \pm 10 $^{\circ}$ (Optional tilting device)							
	Column	Speed	Maying speed				Max. 10		vice)			
	Column	Material	Moving speed				Gat					
Measuring			loading woist-t	02 1.0	72 1.0	0010	T	r	66 1.0	0216	72 1/	
stand	Base	Permissible	loading weight	82 kg	72 kg	89 kg	79 kg	76 kg	66 kg	83 kg	73 kg	
		Dimensions	Width	600	rnm	1000) mm	600	m	100	0 mm	
			Depth				450	mm				

Other

Power	Voltage (frequency)				Single-phas	e AC100 V t	o 240 V (50	Hz / 60 H z))		
supply	Power co	nsumption		Max. 670 VA								
	Supply pressure						0.45 MPa t	to 0.7 MPa				
Air supply	Working	Working pressure			-		0.4 /	MPa	-	-	-	
(For anti- vibration table)	Air consu	mption	-		•	0.7	l L/min (N	1ax. 10 L/mi	in)	-		
	Position of supply port						Back of n	nain unit	•	-	-	
·	Air supply	Air supply connecting port		Rc´	Rc1/4 male screw (Outside diameter Φ6 mm one-touch pipe joint for tube)							
	Main	Dimensions	Width	960	960	1360	1360	960	960	1360	1360	
Dimensions			Depth	762	762	840	840	762	762	840	840	
and weight	unit		Height	1478	1678	1673	1893	1478	1678	1673	1893	
		Weight	L	245	255	395	405	250	260	400	410	
		Temperature of a	ccuracy guarantee	20 °C ± 2 °C	(Ratio of te	mperature cl	nange: ±0.5°C	/within an h	our, 0.1℃ /wi	thin one mea	suring time)	
	Temperature	Temperature of op	eration guarantee	10 °C to 30 °C								
Ambient temperature		Storage tem	perature	5 ℃ to 40 ℃								
temperature	11	Humidity of open	ration guarantee	40 % to 80 % (without condensation)								
	Humidity	Storage hum	nidity		•	80 % oı	lower (with	out conder	nsation)	•	•	

 $[\]ensuremath{^{*}}$ Power and air supply and a connecting hose are required before the delivery.

Standard Configuration and Accessories

01) Set of measuring unit Hybrid detector with dual sensor technology

Tracing driver

Measuring stand column Measuring stand base

Anti-vibration table and bench (Standard for DX model, Option for SD model)

02) Set of data processor Driver unit

PC Keyb

Keyboard Mouse

Liquid crystal display

A4 color inkjet printer (Standard for DX model, Option for SD model)

03) Roughness and contour profile measurement and analysis integrated software; ACCTee

04) Master ball calibration unit [E-MC-S65A]

05) Block gauge unit $[\, \hbox{E-MG-S39A} \,]$

06) Reference specimen [E-MC-S24B]

07) Stylus [DM48507]

08) Stylus [DM48775] 09) Oil clay

10) Set of hex wrenches

11) Flat-blade screwdriver

12) Lubrication oil

13) Accessory carrying case

14) Inspection certificate

15) Operation manual

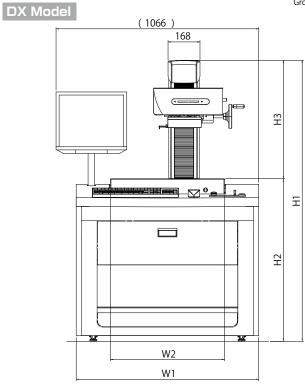


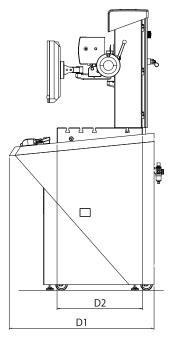
^{*} Contents of the specification may be changed without any notice due to product modifications.

External Dimensions and View

						Main unit dimentions					Measuring range (mm) Base ((mm) Weigh		nt (kg)
					Width	Depth	Height	Table height	Column height	X-axis (Tracing driver)	Z-axis (Column)	Width	Depth	Main unit weight ※1	Max. loading weight
M	odel		Code		W1	D1	H1	H2	H3			W2	D2		
DX	12	K2	A B	Α	960	762	1478	855	623	100	250	600	450	245(275)	82
DX	13	NZ	C	В	960	762	1678	855	623	100	450	600	450	255(285)	72
SD	12	K2	D	Α	600	638	1441	818	623	100	250	600	450	120(145) 242	82
3D	13	NZ	F	В	600	638	1641	818	623	100	450	600	450	130(155) 252	72

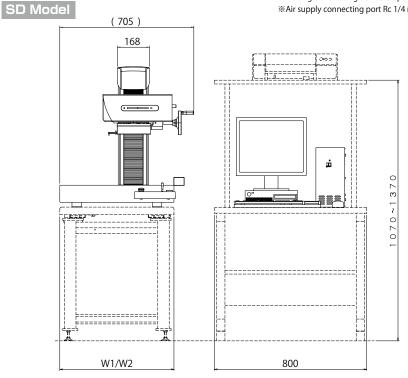
**1 Weights in parentheses include PC, driver unit, monitor and printer (DX model only).
Gross weights in lower lines include optional anti-vibration table, bench, rack and printer (SD model only).

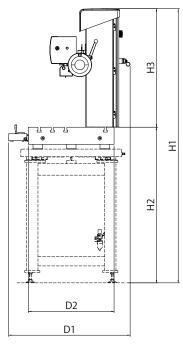




**Tracing driver tilting device is optional.

*Air supply connecting port Rc 1/4 male screw (outside diameter Φ 6 mm one-touch pipe joint for tube)





**Tracing driver tilting device is optional.

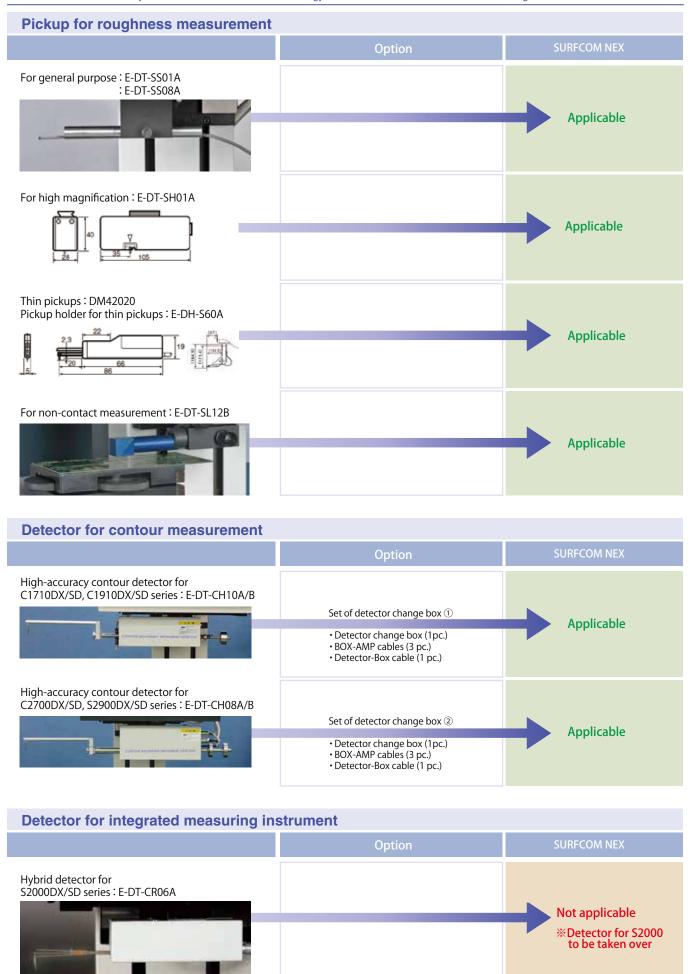
% Air supply connecting port Rc 1/4 male screw (outside diameter Φ 6 mm one-touch pipe joint for tube)

Replaceable styli for Hybrid Detector with Dual Sensor Technology [E-DT-CR14A]

Name	Model	External view	Specifications	Remarks
General purpose	DM48505	13 10 - 01.2 02.7 46 57.6	2 μ mR, 60 ° conical diamond, 0.75 mN LH= 50 LV= -14.35	Standard length For roughness and contour measurement
General purpose highly rigid stylus	DM48507	15 10 46 58.5	2 μ mR, 60 ° conical diamond, 0.75 mN LH = 50 LV= -15.5	Standard length Standard accessory for SURFCOM NEX 100 For roughness and contour measurement
	DM48775	2 96 108.5	25 μ mR, 24 ° conical carbide, 0.40 mN LH= 100 LV= -21.5	2x length Standard accessory for SURFCOM NEX 100 For contour measurement only
Highly rigid stylus for contours	DM48508	21 16 96 108.5	500 μ mR, ruby ball, 0.75 mN LH= 100 LV= -21.5	• 2x length • For contour measurement only
	DM48509	20 121 133.5	500 μ mR, ruby ball, 3.2 mN LH= 125 LV= -25.5	• 2.5x length • For contour measurement only
Right angle stylus	DM48511	13.5 14 9 - 01.2 46 58.5	2 μ mR, 60 ° conical diamond, 0.75 mN LH= 50 LV= -14.5	Standard length Offset: 13.5 mm For roughness and contour measurement
Small hole stylus	DM48513	2 1. 15 46 57.6	2 μ mR, 60 ° conical diamond, 0.75 mN LH= 50 LV= -5.025	Standard length Probe height: 2.0 mm For roughness and fine contour measurement
Extra small hole stylus	DM48514	0.6 0.7 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	2 μ mR, 60 ° conical diamond, 0.75 mN LH=50 LV= -4.625	Standard length Probe height: 1.0 mm For roughness and fine contour measurement
Deep hole stylus	DM48515	25 46 58.5	2 μ mR, 60 ° conical diamond, 0.75 mN LH= 50 LV= -30.5	Standard length Probe height: 25.0 mm For roughness and fine contour measurement
Fine contours stylus	DM48588	(3) 13 10 - 61.2 62.7 46 57.6	5 μ mR, 30 ° conical diamond, 0.75 mN LH= 50 LV= -14.35	Standard length For roughness and fine contour measurement

Standard Inventory Parts

Detectors Retrofit to hybrid detector with dual sensor technology enables the use of same detectors for existing linear series.

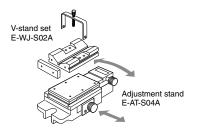


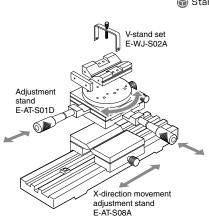
In case your machine is linear series with a detector for standard series, contact your nearest Tokyo Seimitsu.

Adjustment Devices

Name	Model	External view	Orthog	gonal Axis Adjus (mm)	stment	Adjus	rivel stment ad)	Adju	ilt stment ad)	Table Size (mm)	Allowable Load (kg) (net wt.)	Remarks
			Х	Y	Z	Fine	Coarse	Fine	Coarse			Min. reading
Adjustment stand	E-AT-S01D		50	50	_	8	360	_	_	Ф150	20 (7)	value: 10 μm
Leveling adjustment stand	E-AT-S02A		_	_	_	-	_	±1.5	_	80×110	15 (3)	_
Adjustment stand	E-AT-S04A		_	±8	-	±3	_	-	_	80×125	15 (8)	_
X-direction movement adjustment stand	E-AT-S08A		400	-	-	-	_	-	_	150×150	20 (25)	_
3D fine adjustment device	E-AT-S10A		55	55	28	_	_	-	_	75×40	1 (3.4)	Straightness: 0.03 mm
1-axis ultra precision fine adjustment stand	E-AT-S11B		-	50	_	_	_	_	-	125×150	20 (4.9)	Straightness: 3.0 μ m Min. reading value: 10.0 μ m
Swivel fine rotation stand	E-AT-S12A		_	-	_	±5	360	_	_	Ф90	3 (0.58)	Min. reading value: 5 '
1-axis precision fine adjustment stand	E-AT-S13B		_	10 (Coarse: 10 μ m Fine: 0.5 μ m)	_	-	_	_	_	60×60	10 (0.7)	Straightness: 3.0 μ m Min. reading value: 0.5 μ m
Tilting stand	E-AT-S64B		-	-	_	-	_	±20	_	60×120	10 (1)	Min. reading value: 5 '
Universal stand	E-WJ-S03A		-	-	_	-	360	-	±90	Ф110	3 (2.5)	X/Y-direction adjustment
Column rotation spacer	E-CS-S129A		-	-	H: 100	-	360	_	_	_	_	Inserted between table and column
Column spacer	E-CS-S128A		-	-	H: 100	-	-	-	-	_	-	Inserted between table and column
Tracing driver spacer	E-CS-S33A		-	L:70	_	-	-	-	_	_	-	Inserted between column and tracing driver
Tracing driver tilting device	E-CA-S85A E-CA-S92A		-	-	-	-	-	-	±15	-	-	For contour measurements E-CA-S85A: For tracing driver 100 mm E-CA-S92A: For tracing driver 200 mm

Sample Adjustment Stand /Holder Configurations







Holders

Name	Model	External view	V Holder (mm)	Chucking (mm)	Vice (mm)	Clamp (mm)	Flat Surface (mm)	Allowable Load (kg) (net wt.)	Remarks
Double-side open vice	E-WJ-S01B		_	_	OD: 38 to 105 ID: 59	_	_	5 (0.8)	Consult us when combining with the tilt stand.
V-stand set	E-WJ-S02A		Ф1 to 150	_	_	_	_	(1.5)	Provided with workpiece clamper
V-stand holder set	E-WJ-S04A		Ф12 to 150	_	_	_	-	(3)	Two pieces set for T-groove clamp.
Compact stand	E-WJ-S05A		Ф4 to 10	_	_	_	-	(0.4)	-
Load plate	E-WJ-S06A		_	_	_	_	150×150 angle plate	(1)	-
Static electricity holding plate	E-WJ-S11A		-	-	-	_	80×130 angle plate	(1.3)	Holding strength: 0.2 kg Ideal for paper, aluminum, and film
Scroll chuck	E-WJ-R01C		-	OD: Φ2 to 75 ID: Φ56 ~ 91	-	_	_	(1)	-
Iris chuck	E-WJ-R10A			OD: Φ5 to 110				(3)	Manufactured after receipt of
IIIS CHUCK	E-WJ-R378A			OD: Φ5 to 150				(5)	order
Clamp set	JC-3		-	_	_	Height 40 to 60	-	_	-
Ceramic load plate	E-WJ-S252A	****	_	_	_	_	300×300 angle plate	(5.3)	Manufactured after receipt of order
Ceramic load plate	E-WJ-S234A	•••	_	_	-	-	500×500 angle plate	(15)	Manufactured afterreceipt of order
Sample Adjus	tment Stand							Standa	rd Inventory Parts
/Holder Confi	gurations	Double-side E-WJ-S01B Universal s E-WJ-S03/	tand	V-holder set E-WJ-S04A	X-direction move adjustment stand E-AT-S08A	adju E-A	Scroll chuc E-WJ-R01		Universal stand E-WJ-S03A Adjustment stand E-AT-S04A

Tracing driver

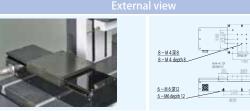
Name	Model	Spe	cifications		External view	
		Measuring OD / length	Φ12 mm to Φ20 mm 30 mm to 150 mm Φ20 mm to Φ150 mm	ļ .	221 160	
Outer periphery roughness	E-RM-S85B		30 mm to 250 mm	<u> </u>		
tracing driver	E-KIVI-303D	Peripheral velocity	0.3, 0.6, 1.5 mm/s		103	
		Max. loading weight	5 kg		102	
		Weight	Approx. 7 kg			
D		Measuring radius	0.25 mm to 40 mm	[••••	
Round surface roughness	E-RM-S84A	Rotation accuracy	\pm 0.25 μ m (180 ° arbitrary)			
tracing driver		Peripheral velocity	0.3mm/s (stepless)		130 115	
		Weight	Approx. 15 kg	,	255	
/-axis fixed pitch		Drive range	13 mm		Tracing driver(100mm)	
racing driver for		Min. feed pitch	0.001 mm		• • • • • • • • • • • • • • • • • • •	
measurement (Detector move-	E-DH-S173A	Number of feed line	2 to 4001 lines		009 15	
		Straightness accuracy Table surface	1 μm	III	Y DRIVER E-DH-S173A	
ment type)		Table surface dimensions	_		Pickup Pickup holder E-DT-SS01A F-DH-S151A Manual grip	
		Max. loading weight			F	
		Drive range	50 mm			
		Min. feed pitch	0.001 mm			
	E-YM-S06A	Number of feed line	2 to 4001 lines			
		Straightness accuracy	0.05 + 3L/1000 μm			
		Table surface dimensions	80 × 120 mm			
		Max. loading weight	5 kg		3-M5深10/	
		Drive range	100 mm		25 9 - M 4 , \$\pi 8	
		Min. feed pitch	0.001 mm		28	
	E-YM-S12A	Number of feed line	2 to 4001 lines			
	E-11VI-312A	Straightness accuracy	$0.05 + 3L/1000 \ \mu \text{m}$			
'-axis fixed pitch		Table surface dimensions	100 × 120 mm			
racing driver for		Max. loading weight	10 kg		3-M5梁10	
BD roughness measurement		Drive range	150 mm		9-M4, #8	
Workpiece novement type)		Min. feed pitch	0.001 mm			
почетнені туре)		Number of feed line	2 to 4001 lines			
	E-YM-S07A	Straightness accuracy	0.05 + 3L/1000 μm		75 150 75 69.5	
		Table surface dimensions	120 × 150 mm			
		Max. loading weight	5 kg		3.—M.5深IQ 177	
		Drive range	200 mm		160	
		Min. feed pitch	0.001 mm		9-M4. #8	
		Number of feed line	2 to 4001 lines			
	E-YM-S08A				100 150 100 90	
		Straightness accuracy Table surface	0.05 + 3L/1000 μ m			
		Table surface dimensions	150 × 150 mm			
		Max. loading weight	10 kg		3-M5深10	

CNC Table

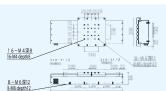
The standard measuring system can be automated by adding a CNC table unit.

CNC table is controlled, and fully automatic measurements can be performed from the ACCTee integrated measuring software. The Y-axis and θ -axis CNC table can be rearranged as needed in order to configure the system to suit the workpiece.

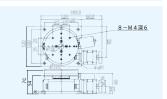
Name	Model	Specific	cations	
		Travel	100 mm	
		Max. travel speed	50 mm/s	
Y-axis CNC table (100mm)	E-AT-S105A	Positioning accuracy	20 μm	
(100mm)		Max. load	30 kg	
		Weight	Approx. 19 kg	
		Travel	200 mm	
		Max. travel speed	50 mm/s	
Y-axis CNC table (200mm)	E-AT-S106A	Positioning accuracy	20 μm	1
(20011111)		Max. load	30 kg	
		Weight	Approx. 22 kg	
		Travel	360°	
		Max. travel speed	20°/s	
θ -axis CNC table (horizontal)	E-AT-S107A	Positioning accuracy	0.03 °	Carrie of the Ca
(Horizontal)		Max. load	15 kg	
		Weight	Approx. 2.5 kg	
		Travel	360°	
		Max. travel speed	20°/s	
θ -axis CNC table (vertical)	E-AT-S108A	Positioning accuracy	0.03 °	The same
(12.2.2007)		Max. load	5 kg	
		Weight	Approx. 3.2 kg	



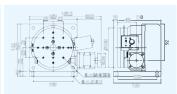






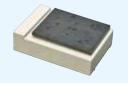


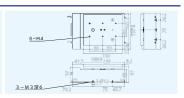




Automatic Adjustment Stand

		Leveling range	± 2°
2-axes auto leveling table	E-AT-S62A	Max. load	5 kg
		Weight	4 kg





Calibrators

Name	Model	External view	Specifications	Remarks
Reference specimen	E-MC-S24B	B10000 B10000	Calibration surface : Approx. 3.1 μ m Ra Stylus check surface: Approx. 0.4 μ m Ra Actual measured value denoted.	For sensitivity calibration and for stylus checkStandard accessory for SURFCOM NEX
Level difference reference specimen	E-MC-S57A	DEC DEC	Large range : Approx. 20.0 μ m Small range : Approx. 2.0 μ m Actual measured value denoted.	For sensitivity calibration and stylus check
Magnification calibrator	E-MC-50B	50 180	Narrow range accuracy : $0 \text{ to } 10 \ \mu\text{m} \pm 0.1 \ \mu\text{m}$ Wide range accuracy : $0 \text{ to } 400 \ \mu\text{m} \pm 1.0 \ \mu\text{m}$	· For magnification calibration
Master ball calibration unit	E-MC-S65A	Alloy difference block Master bal Last Stalk Value Convenies 120 Mas. 126 Smmi	Master ball : Radius Φ6.35 mm : Sphericity 0.13 μm Level difference block : Step value 4 mm, 8 mm Y-axis direction adjustment table : Max. stroke 13 mm	For measurements with stylus pointing downwards With block gauge unit [E-MG-S39A] Standard accessory for SURFCOM NEX
Small hole stylus Master ball calibration unit	E-MC-S59C	Gage black Calibration ball	Reference sphere: Φ1.5 mm Block gauge: 1.5 mm	For measurements with stylus pointing downwards With block gage unit
Pitch gage	E-MG-S02A	• 11111 • 38	Pin diameter: 7.9 mm Pitch: 15 mm	• Dimensions: 144 mm (W) x 38 mm (D) x 49 mm (H)
Stylus check master	E-MG-S24A	90° 1Edge line length)	Tip radius: 0.1 μ m or less. Material: Knife edge diamond	-

Peripherals

Name	Model	External view	Specifications	Remarks
Bench for desktop anti-vibration table	E-VS-S218A	510 430	_	 Dimensions: 510 (W) x 430 (D) x 643 (H) mm Weight:23kg For E-VS-S213A
Desktop anti-vibration table	E-VS- S213A	60 + 1 + 1 + 1 + 1 + 1 + 1 + 1 + 1 + 1 +	Anti-vibration method: Diaphragm air spring Natural frequency: 2.5 Hz to 3.5 Hz Load weight: 200 kg	 Dimensions: 600 (W) x 530 (D) x 60 (H) mm Air supply: 350 kPa to 700 kPa Weight: 27 kg Requires nylon tube with φ6 mm outside and φ4 mm inside diameter for quick joint connecting aperture.
Desktop large anti-vibration table	E-VS-S45A		Anti-vibration method: Diaphragm air spring Natural frequency: 4 Hz Load weight: 300 kg	• Dimensions: 1000(W) x 750(D) x 143(H) mm • Air supply: Pump • Weight: 80 kg
Anti-vibration	E-VS-R16A	980 (1074) 780 (824) 700 (700)	Anti-vibration method: Diaphragm air spring Natural frequency: V: 2 Hz; H: 2.2 Hz Load weight: 250 kg	• Dimensions: 980 (W) x 780 (D) x 700 (H) mm • Air supply: 350 kPa to 700 kPa • Weight: 170 kg
table	E-VS-S21B	760 (850) 560 (600) Dimentions in (parentheses) are for the E-VS-S21B	Anti-vibration method: Diaphragm air spring Natural frequency: V: 1.6 Hz; H: 2 Hz Load weight: 550 kg	 Dimensions: 1100 (W) x 850 (D) x 700 (H) mm Air supply: 350 kPa to 700 kPa Weight: 340 kg
System rack	E-DK-S24A	W 420-	-	 Dimensions: 800 (W) x 800 (D) x 1070 mm to 1370(H) mm Weight: 44.5 kg
·	E-DK-S25A		-	• Dimensions: 1200 (W) x 800 (D) x 1070 mm to 1370 (H) mm
Side desk	E-DK-S10A	700	_	• Dimensions: 400(W) x 700(D) x 700(H) mm
High magnification	E-CV-S02A	Transparent vinyl sheet W Transparent acrylic plate	_	 Used with desktop anti-vibration table / stand for roughness measuring Dimensions: 750 (W) x 614 (D) x 810 (H) mm Weight: 8 kg For SURFCOM NEX SD type
dust cover	E-CV-S03A		-	Used with desktop anti-vibration table / stand for contour profile measurement Dimensions: 1000 (W) x 629 (D) x 810 (H) mm Weight: 13 kg For SURFCOM NEX SD type
Dust cover	E-CV-S25A	1070 1050 1050 1050 1050 1050 1050 1050	_	 Used with E-VS-S21A anti-vibration table Dimensions: 1070 (W) x 750 (D) x 1050 (H) mm Weight: 20 kg
Measuring position verification unit	E-MA-S81A	Microscope X25 Stand Microscope knob	Magnification: ×20 Focal distance: 60 mm	· Stand type
Light	E-MA-S84A	Fine movement knob Flex ble arm Fixing knob 115 Fixing knob 70	_	· Stand type
Power transformer box	E-TF-R25A	300 NE 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0	Input: 90 V to 240 V Output: 100 V Capacity: 2.1 kVA	 Specify the input voltage. Dimensions: 300 (W) x 350 (D) x 296 (H) mm Weight: 45 kg



Integrated Measurement and Analysis Software



ALL in the Document!

ACCTEE Surface Texture Measurement and Analysis System

Versatile measurement and analysis functions

Various guidance functions for beginners

Change Analysis Conditions with Preview Function

With ACCTee, you can set and change the roughness parameter calculation standard, cutoff filter, notch level, deletion length and other conditions. The range of the waveform data used for the roughness parameter calculation can be set to any value. The preview function also allows you to optimum form remove (tilt correction) can also be selected. The specified area and conditions can be cleared and changed quickly and easily.



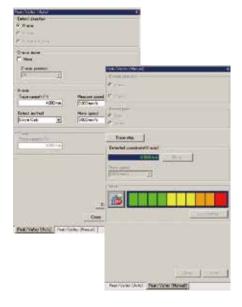
Analysis condition display



Preview display of changed analysis condition

Roughness Peak and Valley Detection Function

ACCTee detects the maximum point (minimum point) and automatically shifts the stylus to the maximum point (minimum point) as the peak and valley function traces the cylindrical profile, convex, concave, and spherical profile using the stylus. In manual operation, the position is reported by an alarm.



Roughness Curve Trace Function

As the profile traced by the roughness stylus is displayed, the measurement area can be set on the screen.

Level Difference Parameter

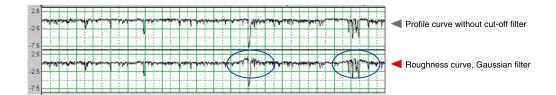
Level differences can be measured on the concave and convex profile. The measurement, average height, maximum height, minimum height, and area can be calculated from the data.

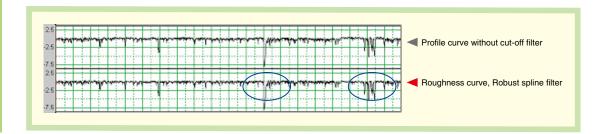
Wear-out Analysis for Roughness Curve Data

The degree of wear can be calculated by overlapping and displaying two roughness curves and calculating the differences between the data.

Robust Spline Filter

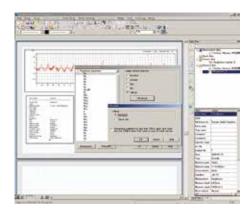
Various filters are available for roughness measurement and analysis, including robust spline filter. The robust spline filter dissolves distortion caused by the phase-compensated type filter with distinguished peak and valley on roughness waviness.





Automatic Pass/Fail Judgment under 16% Rule (JIS2001 Standard)

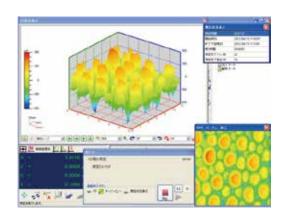
In the ACCTee analysis process, the 16% rule and the max rule are standardized for the tolerance criteria of the roughness evaluation parameters. With the 16% rule, if the measurement value for the multiple standard length that exceeds the tolerance is below 16%, it is assumed to pass. With the Max rule, all multiple standard length measurement values must not exceed the allowable tolerance.



3D Roughness Measurement and Analysis

Functions support 3D roughness analysis. (Optional expanded hardware required) It is possible to obtain up to 4000 scanning lines and 80 million data.

3D analysis can be performed with versatile visual displays.

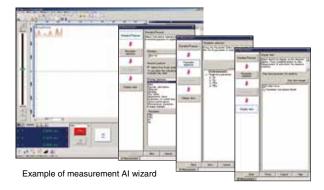


Surface Texture Measurement and Analysis System

Versatile wizard functions support operators

Measurement Al Wizard

For the measurement AI function of the ACCTee, the parameters and analysis condition appropriate for the roughness standard and evaluation purpose can be specified. In addition, the optimum measurement condition can be specified by executing trial measurement. The analysis item for the measurement data selected on the document can be displayed by selecting the display items at the end.



Pickup Calibration Wizard

Sensitivity calibration is executed by selecting any of the following three options: depth specimen; magnification calibration unit; and reference specimen.

Next, the calibration condition is specified (inputting reference value), the installation method for the calibration unit and the measurement start position are confirmed, then calibration is executed.



Example of pickup calibration wizard

Calibration Alarm and Historical Management

ACCTee can accept any time as the time of calibration. In addition to the probe replacement time, a calibration alert based on measurement frequencies or lapsed days is displayed, helping maintain accurate and stable measurement by ensuring periodical calibration.

Stylus Tip Check Wizard

ACCTee can use a depth specimen or reference specimen for the stylus tip check. The tip of the stylus is subject to increasing wear so a regular check is necessary to maintain accurate measurement. With the wizard's guidance, anyone can easily check the stylus tip.

Parameter Figure and Symbol Input Wizard

The same symbols used in the design diagram can be input into the design values of the analysis condition and parameter pass/fail judgment.





Example of parameter figure and symbols wizard

			Surface Texture Measurement and Analysis Program					
Standard			Complies with JIS2001, JIS1994, JIS1982, ISO1997, ISO1984, DIN1990, ASME2002/1995, CNOMO					
Parameter			Ra, Rq, Ry, Rp, Rv, Rc, Rz, Rmax, Rt, RzJ, R3z, Sm, S, RΔa, RΔq, Rλa, Rλq, TlLT A, Ir, Pc, Rsk, Rku, Rk, Rpk, Rvk, Mr1, Mr2, VO, K, tp, Rmr, Rmr2, Rσc, AVH, Hmax, Hmin, AREA, NCRX, R, Rx, AR, NR, CPM, SR, SAR					
Parameter j	udgment		The judgment result can be displayed by standard, average value, maximum value, minimum value, and 16 % rule					
Evaluation	curve		Profile curve, roughness curve, filtered waiveness curve, filtered center line waviness curve, rolling circle waiveness curve, rolling circle center line waiveness curve, ISO13565-1(DIN4776) roughness curve, roughness motif curve, waiveness motif curve, envelope waviness curve					
Surface cha	racteristic disp	lay	Bearing area curve, power spectrum curve, amplitude distribution function, ISO13565-2 Bearing area curve, ISO13565-3 Bearing area curve, peak height distribution graph/list, auto correlation graph (option), wear-out amount analysis (two arbitrary curves), overlapping analysis (ten curves max.)					
Form remove (tilt correction)		on)	Least square straight line correction, n-dimension polynomial (n=2 to 9) correction, both ends correction, least square circle correction, least square oval correction, spline correction, robust (spline) correction (arbitrary or first or latter half of the setting range can be specified for all the options)					
	Туре		Gaussian phase compensation filter, phase uncompensation type 2RC filters, phase compensation 2RC filters, spline filter, robust (spline) filter					
Filter	Cutoff wave	elength	0.008, 0.025, 0.08, 0.25, 0.8, 2.5, 8, 25, 50 mm (9 levels), arbitrary (in the range of 0.001 mm to 51 mm)					
riiter) Ch	Cutoff ratio	1/30, 1/100, 1/300, 1/1000, arbitrary (from 1/10)					
	λ s filter	Cutoff wavelength	0.08, 0.25, 0.8, 2.5, 8, 25, 80 μ m (7 levels), arbitrary (in the range of 0.05 μ m to 0.08 μ m)					
Stylus calibration		1	Can be selected from step reference specimen (JIS standard), magnification calibration unit, and reference specimen. Maximum 20 units of stylus calibration information can be registered (deadline for the calibration time can be specified)					
Number of data points			300,000 points max.					
Magnification	Vertical Vertical		Automatic, arbitrary value (unit: 0.01), upper/lower limit value 50, 100, 200, 500, 1k, 2k, 5k, 10k, 20k, 50k, 100k, 200k, 500k, 1000k, 200k, 5000k, 10000k times					
display			Automatic, arbitrary value (unit: 0.01), upper/lower limit value 50, 100, 200, 500, 1k, 2k, 5k, 10k, 20k, 50k, 100k, 200k, 500k, 1000K times					



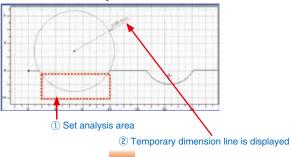
ALL in the Document!

CCTee Contour Profile Measurement and Analysis system

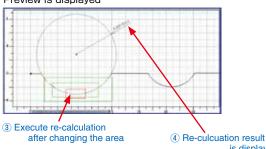
Calculation Result Preview Function Patent pending

Calculation results can be displayed before output. As a calculation range is changed, a result can be previewed timely. Try & Error analysis is available as many times as necessary while viewing calculation results, which enhances operational efficiency.

Execute element analysis







Trv & Error

Try & Error analysis is available as many times as necessary

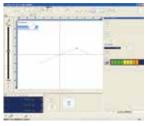
is displayed



Peak and Valley Function

There are two modes in this function: Auto mode, in which the minimum point is automatically detected; and Manual mode, in which you turn the knob of the adjustment platform or the tracing driver and changes in color and sound alert you when the level mark on the screen.

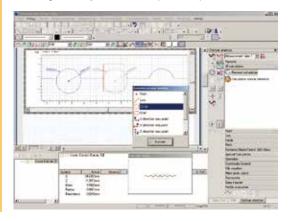




Manual mode maximum point detection

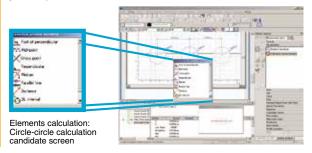
Al Function (automatic element judgment) Patented

The points, straight lines, and circles of the basic elements are automatically extracted by turning on the AI function and by selecting the specified area of the measurement data. This eliminates the specification of the menu and icon in each case, which significantly reduce the operation procedure.



Element Calculation with Icon Guidance

When making a new calculation from any of the multiple elements already created, all possible choices are displayed. Multiple inter element calculations can also be selected to suit your requirements.



Work Trace Function

As this function displays a manually traced profile, it is ideal for determining the measurement limit point when measuring to the edges of a wall or valley with reference to the trace start or end points. It is also useful in situations where a visual check is difficult, such as the inside of a hole. As the start point and the end point can be specified in the profile traced on the screen, the measurement will never fail. The screen changes to show the real-time status of the profile being measured when measurement starts.





Real-time display

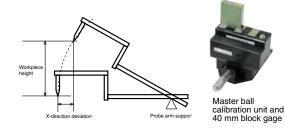
2.1

Contour Profile Measurement and Analysis system

Master Ball Calibration Function Patented

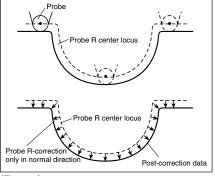
Circle correction calculation

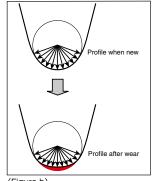
Since the probe moves in a circular motion vertically around the support on the contour measuring instrument's probe arm, X-axis data also has errors because the probe tip position also moves in the X-axis direction. These error elements must be corrected in order to achieve high measuring accuracy. The ACCRETECH contour measuring system performs calibration using a master ball calibration unit which enables simple circle error as well as tip R error calibration.

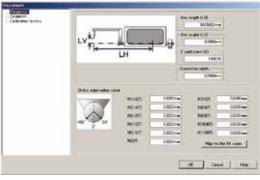


Tip R-correction

Although the contour measuring instrument's probe tip is R-shaped, tip R-correction is an indispensable factor for high measuring accuracy. Measurements are taken from the center of probe tip R and correction is performed by offsetting in the normal direction at 11 dividing points on the tip (Figure a). Though there is no problem with fixed quantity correction when probe tip R is near maximal generalized roundness zero, large errors occur in the correction amount due to tip R processing tolerance error or wear after long term use (Figure b). In order to make it possible to quickly detect errors, ACCRETECH calculates tip R for every 10° and generates correction values. More than simple R-correction, an original algorithm monitors the status of the probe tip. The operator is alerted by an error indicator whenever the correction value is outside preset limits.







(Figure a)

(Figure b)

Master ball correction screen

Stylus Calibration Wizard

Stylus calibration is performed by the master ball calibration unit. During masterball measurement and level difference measurement, tip R correction and arc error correction can be executed automatically or manually. The wizard takes you through all necessary steps in the following order: calibration condition (inputting reference value) setting, placement of the calibration unit, confirmation of measurement start point, and execution of calibration.



Calibration Alert

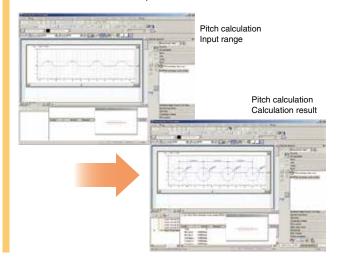
Calibration can be specified at any time. In addition to the stylus replacement time, a calibration alert based on measurement frequencies or elapsed time is displayed periodically, ensuring accurate, stable measurement on a continuous basis.

Calculation Point Manual Input

When analyzing the same profile repeatedly, it is possible to switch from manual operation to targeted analysis during CNC execution by setting the condition for recalculation, enabling detailed analysis.

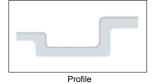
Pitch Calculation Function

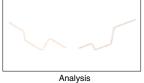
For the same multiple profiles composed of circles and straight lines, the pitch between line intersections or the pitch between circle centers can be automatically output just by specifying the arc with the mouse. Analysis efficiency can be improved by using the dimension line auto output function at the same time.



Profile Synthesis Function

Even for a workpiece that requires measurement for multiple times because of the limitation of the stylus angle, the analysis can be made by combining the data into one using the profile synthesis function.







sis Measurement

Edge Detection Measurement Patent pending

You can set the instrument to detect edges during measurement and automatically complete measurement. This is useful when you want to measure the far end of the edge.

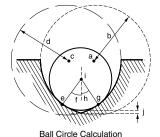
Import External Data

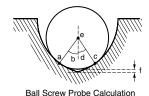
CAD IGES/DXF data and Calypso Curve measurement data* are read and evaluated with contour analysis.

※ Nominal value data output by Calypso optional Form data ASCII input/output program.

Ball Screw Calculation Function (Option)

Two calculation methods are supported: approximation for a round ball screw groove part, and a method that calculates the groove profile as-is. A lead angle projection function makes it possible to analyze and project data measured in the edge direction in groove and line directions.





Best Fit Function (Option)

Best fit function calculates points that are symmetrical to the curve, providing measured data for a non-spherical surface and shifting the origin so these points are the vertices. The origin shift can be configured so X and Z rotation are performed independently, or in combination.

Non-spherical Surface Nominal Value Generation Function (Option)

This function generates non-spherical surface nominal values using a non-spherical surface calculation formula. After inputting the conic constant, circle radius, number of expression terms, non-spherical surface coefficient value, and other parameters as calculation expression variables, the software generates nominal value point data for a non-spherical surface profile.

		Contour Profile Measurement and Analysis Program
Al function		Automatic distinction of point, straight line, circle
		Automatic distinction of the combination executable of calculation between two elements (point-point, point-straight line, point-circle, point-oval, straight line-straight line, straight line-circle, straight line-oval, circle-circle, circle-coval, oval-oval)
Arithmetic processing	Point	Point, maximum point, foot of perpendiular, mid-point, intersection, contact point, point on straight line, point on circle, inflection point
	Straight line	Straight, perpendicular, median, contact, parallel, bisector, virtual
	Circle	Circle, partial circle, contact circle, virtual circle, oval
	Pitch	Pitch between line cross, pitch between circle centers
	Distance	Distance, path
	Angle	Intersection angle, complementary angle, supplementary angle
	Coordinate	X coordinate difference, Z coordinate difference, angular dliference, radius vector difference
	Step difference	Average step, max. step, min. step
	Area	Area
	Arithmetic	Addition, subtraction, multiplication, division, power operation, surplus, absolute value, square root
	Statistics	Average, max. value, min. value, standard deviation, total sum
	Special calculation	Over-pin calculation
Coordinate control		Origin setting, parallel move, rotary move, each axis setting
Measurement support function		Re-measurement function, Al function, wizard functions, self-diagnosis function, CNC function, peak and valley function, work trace function, dimension line display function, profile synthesis function, collation function with form and nominal value, coordinate system automatic setting function
Calculation support function		Infinite cursor, cursor form vertical/horizontal switch, one point micro motion, setting of error band
Data file input and output		Input of point sequence, text, CSV, IGES, DXF data and Calypso data
Stylus calibration		Automatic and manual calibration by master ball calibration unit. Maximum 20 units of stylus calibration information can be registered (deadline for the calibration time can be specified)
Measure pitch		0.01 μ m to 1000 μ m
Number of data points		300,000 points max.
Magnification display	Vertical	Arbitrary value (unit: 0.01), automatic and 0.01 to 10,000,000 times
	Horizontal	Arbitrary value (unit: 0.01), automatic and 0.01 to 10,000,000 times

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